

INFORMATION DISCLOSURE STATEMENT BY APPLICANT	Application No.	10/815,905
	Filing Date	March 31, 2004
	First Named Inventor	Lin et al.
	Art Unit	2874
(Multiple sheets used when necessary)		Examiner
SHEET 1 OF 2		Attorney Docket No.
		QCO.094.A/061113

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Examiner Initials	Cite No.	Document Number Number - Kind Code (if known) Example: 1,234,567 B1	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear
	1	4,863,245	9/5/1989	Roxlo	
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Examiner Signature	Date Considered
*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 809. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

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SHEET 2 OF 2		Attorney Docket No.	QCO.094A/061113

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Examiner Initials	Cite No.	Foreign Patent Document Country Code-Number-Kind Code Example: JP 1234567 A1	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear	T ¹
	26	CH 680534	9/15/1992	Landis & GYR Betriebs AG		X-abstract
	27	EP 1 170 618	1/9/2002	Sony Corp		
	28	JP 2003195201	7/9/2003	Fuji Photo Film Co		X
	29	WO 03/046508	6/5/2003	Biomicronarrays		
	30	WO 04/000717	12/31/2003	Filtronic		
	31	WO 04/015741	2/19/2004	Unaxis USA		

NON PATENT LITERATURE DOCUMENTS

Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ¹
	32	Hall, Integrated optical interferometric detection method for micromachined capacitive acoustic transducers, App. Phy. Let. 80:20(3859-3961) May 20, 2002	
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